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TEST REPORT

Application No.:HKEM2202000204ATApplicant:Nacon (HK) Limited

Address of Applicant: Unit 1505, 148 Electric Road, North Point, Hong Kong

Equipment Under Test (EUT):

EUT Name: PS4 Wireless Controller

Model No.: BB4487

 FCC ID:
 2AVPR-4487DBT

 IC:
 25872-4487DBT

HVIN: 4487DBT

Standard(s): 47 CFR Part 1.1307, Part 1.1310

KDB447498D01 General RF Exposure Guidance v06

RSS-102 Issue 5

Date of Receipt: 2022-02-20

Date of Test: 2022-02-20 to 2022-02-28

Date of Issue: 2022-03-01

Test Result: Pass*



Law Man Kit EMC Manager

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Unless otherwise stated the results shown in this test report refer only to the sample(s) tested and such sample(s) are retained for 30 days only.

^{*} In the configuration tested, the EUT complied with the standards specified above.



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	Revision Record						
Version	Version Chapter Date Modifier						
01		2022-03-01		Original			

Authorized for issue by:		
	Panner	
	Panny Leung	-
	/Project Engineer	Date: 2022-03-01
	Law	
	Law Man Kit	
	/Reviewer	Date: 2022-03-01



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2 Test Summary

Radio Spectrum Technical Requirement							
Item	Standard	Method	Requirement	Result			
	47 CFR						
RF Exposure	Part 1.1307,	CFR 47 Part 1.1310	CFR 47 Part 1.1310	Pass			
	Part 1.1310						

Radio Spectrum Tec	hnical Requirement			
Item	Standard	Method	Requirement	Result
RF Exposure	RSS-102 Issue 5	RSS-102 Section 2.5.1	RSS-102 Issue 5	Pass

Declaration of EUT Family Grouping:

None.

Abbreviation:

Tx: In this whole report Tx (or tx) means Transmitter.

Rx: In this whole report Rx (or rx) means Receiver.

RF: In this whole report RF means Radiated Frequency.

CH: In this whole report CH means channel.

Volt: In this whole report Volt means Voltage.

Temp: In this whole report Temp means Temperature.

 $\label{eq:Humid:$

Press: In this whole report Press means Pressure.

N/A: In this whole report not application.



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4 General Information

4.1 Details of E.U.T.

 Dotails of E.S.II.	
Power supply:	USB 5.0VDC
Test voltage:	AC 120V or DC 5.0V
Cable:	N/A
Antenna Gain:	2.64 dBi
Antenna Type:	PIFA
Bluetooth Version:	4.2
Channel Spacing:	1MHz
Modulation Type:	GFSK, π/4DQPSK
Number of Channels:	79
Operation Frequency:	2402MHz to 2480MHz
Series number:	A1
Hardware Version:	V2.7
Software Version:	V1.25

4.2 Description of Support Units

The EUT has been tested with corresponding accessories as below:

Supplied by client

Description	Manufacturer	Version	SN/Certificate NO
Eclipse test software	Eclipse contributors	Mars.1 Release (4.5.1)	20150924-1200

Supplied by SGS:

Description	Manufacturer	Model No.	SN/Certificate NO
NoteBook (EMC4)	Dell	P75F	N/A



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4.3 Modulation configure

RF software:	FCC_Assist.exe			_
Modulation	Packet	Packet Type	Packet Size	Power
	DH1	Pn9	Default	2
GFSK	DH3	Pn9	Default	2
	DH5	Pn9	Default	2
	2DH1	Pn9	Default	2
π/4DQPSK	2DH3	Pn9	Default	2
	2DH5	Pn9	Default	2

Remark:

1. default value was set in test software as maximum output power setting.



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4.4 Measurement Uncertainty

RF

No.	Item	Measurement Uncertainty
1	Radio Frequency	± 7.25 x 10 ⁻⁸
2	Duty cycle	± 0.37%
3	Occupied Bandwidth	± 3%
4	RF conducted power (30MHz-40GHz)	1.5dB
5	RF power density	1.5dB
6	Conducted Spurious emissions	1.5dB
		4.4dB (30MHz-1GHz)
7	RF Radiated power &	4.7dB (1GHz-6GHz)
/	Radiated Spurious emission test	4.7dB (6GHz-18GHz)
		5.7dB (18GHz-40GHz)
8	Temperature test	± 1 ℃
9	Humidity test	± 3%
10	Supply voltages	± 1.5%
11	Time	± 3%

The U_{lab} (lab Uncertainty) is less than U_{cispr} (CISPR Uncertainty), so the test results

- compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit;
- non-compliance is deemed to occur if any measured disturbance level exceeds the disturbance limit.

According to decision rule based on Clause 4.2 of CISPR 16-4-2, the EUT complied with the standards specified above.



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4.5 Test Location

All tests were performed at:

SGS Hong Kong Limited

Unit 2 and 3, G/F, Block A, Po Lung Centre,

11 Wang Chiu Road, Kowloon Bay, Kowloon, Hong Kong

Tel: +852 2305 2570 Fax: +852 2756 4480

No tests were sub-contracted.

4.6 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

· HOKLAS (Lab Code: 009)

SGS Hong Kong Limited has been accepted by HKAS Executive, on the recommendation of the Accreditation Advisory Board, as a HOKLAS Accredited Laboratory, this laboratory meets the requirements of ISO/IEC 17025:2017 and it has been accredited for performing specific test as listed in the scope of accreditation within the test category of Electrical and Electronic Products.

IAS Accreditation (Lab Code: TL-817)

SGS Hong Kong Limited has met the requirements of AC89, IAS Accreditation Criteria for Testing Laboratories, and has demonstrated compliance with ISO/IEC Standard 17025:2017, General requirements for the competence of testing and calibration laboratories. This organization is accredited to provide the services specified in the scope of accreditation maintained on the IAS website (www.iasonline.org).

The report must not be used by the client to claim product certification, approval, or endorsement by IAS, NIST, or any agency of the Federal Government.

• FCC Recognized Accredited Test Firm(CAB Registration No.: 514599)

SGS Hong Kong Limited has been accredited and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Designation Number: HK0015, Test Firm Registration Number: 514599.

• Industry Canada (Site Registration No.: 26103; CAB Identifier No.: HK0015)

SGS Hong Kong Limited has been recognized by Department of Innovation, Science and Economic Development (ISED) Canada as a wireless testing laboratory. The acceptance letter from the ISED is maintained in our files. CAB Identifier No: HK0015, Site Registration Number: 26103.

4.7 Deviation from Standards

None

4.8 Abnormalities from Standard Conditions

None



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5 Equipment List

Conducted Peak Output Power						
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date	
SMBV100A VECTOR SIGNAL GENERATOR	Rohde & Schwarz	SMBV100A	E234	2021/08/16	2022/08/15	
FSV40 SIGNAL ANALYZER 40GHz	Rohde & Schwarz	FSV40	E235	2021/08/16	2022/08/15	
OSP	Rohde & Schwarz	OSP-B157W8	E242	2021/08/16	2022/08/15	
Cable	Rohde & Schwarz	J12J103539- 00-2	E239	2021/07/15	2022/07/14	
WMS32 Test software	Rohde & Schwarz	N/A	Version 11	N/A	N/A	

General used equipmen	t				
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Digital temperature & humidity data logger	SATO	SK-L200TH II	E232	2021/08/16	2022/08/15
Electronic Digital Thermometer with Hygrometer	nil	2074/2075	E159	2021/08/16	2022/08/15
Barometer with digital thermometer	SATO	7612-00	E218	2021/03/29	2022/03/28
Conditional Chamber	Zhong Zhi Testing Instruments	CZ-E-608D	E216	2021/08/17	2022/08/16



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6 Radio Spectrum Technical Requirement

6.1.1 Test Requirement:

CFR 47 Part 1.1310

Limit:

According to FCC Part1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in Part1.1307(b)

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)				
(A) Limits for Occupational/Controlled Exposure								
0.3-3.0	614	1.63	*100	6				
3.0-30	1842/f	4.89/f	*900/f ²	6				
30-300	61.4	0.163	1.0	6				
300-1,500			f/300	6				
1,500-100,000			5	6				
(B) Limits for General Population/Uncontrolled Exposure								
0.3-1.34	614	1.63	*100	30				
1.34-30	824/f	2.19/f	*180/f ²	30				
30-300	27.5	0.073	0.2	30				
300-1,500			f/1500	30				
1,500-100,000			1.0	30				

f = frequency in MHz

According to IEEE C95.3:2002 section 5.5.1.1, The power density S at a point on the axis at a distance d from a transmitting antenna is given by the Friis free-space transmission formula

$$S = \frac{PG}{4\pi d^2}$$

 $S = power density (mW/cm^2)$

P = the net power delivered to the antenna (mW)

G = gain of the antenna in linear scale

d = distance between observation point and center of the radiator (cm)

^{* =} Plane-wave equivalent power density



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6.1.1 IC Radiofrequncy radiation

According to RSS-102 Issue 5, section 2.5.2 Exemption.

RF exposure evaluation is required if the separation distance between the user and the device's radiating element is greater than 20 cm, except when the device operates as follows:

below 20 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W (adjusted for tune-up tolerance);

at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 22.48/f0.5W (adjusted for tune-up tolerance), where f is in MHz;

at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);

at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1.31 \times 10-2 f0.6834 W (adjusted for tune-up tolerance), where f is in MHz;

at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).



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6.1.2 EUT RF Exposure Evaluation

Antenna Gain: 2.64 dBi

The maximum Gain measured in fully anechoic chamber is 1.84 in linear scale.

Output Power Into Antenna & RF Exposure Evaluation Distance:

For FCC;

Channel	Frequency (MHz)	Conduct power (including Tune-up tolerance) (dBm)	Conduct power (mW)	Power Density at R = 20 cm (mW/cm2)	Limit	MPE Ratios	Result
Low	2402	9.0	7.94	0.0029	1	0.0029	PASS
Middle	2441	8.3	6.76	0.0025	1	0.0025	PASS
High	2480	9.7	9.33	0.0034	1	0.0034	PASS

For IC:

Channel	Frequency (MHz)	Conduct power (including Tune-up tolerance) (dBm)	E.I.R.P (dBm)	E.I.R.P (W)	Limit (W)	Result
Low	2402	9.0	11.64	0.015	2.68	PASS
Middle	2441	8.3	10.94	0.012	2.70	PASS
High	2480	9.7	12.34	0.017	2.73	PASS

Note: 1. Refer to report No. HKEM220200020402 for EUT test conducted power value. requirement.



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7 Photographs

7.1 EUT Constructional Details (EUT Photos)

Refer to the appendices setup, external and internal photos.

- End of the Report -